## Notice of References Cited Application/Control No. 10/813,920 Examiner Andrew Wendell Applicant(s)/Patent Under Reexamination TERVO ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0224665	11-2004	Kokubo, Takeshi	455/411
*	В	US-6,212,410	04-2001	Ishida, Takeshi	455/572
*	С	US-5,987,609	11-1999	Hasebe, Mikio	726/35
*	D	US-2004/0025053	02-2004	Hayward, Philip John	713/201
*	E	US-7,024,698	04-2006	Tanaka et al.	726/26
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	Т	,				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.